ANALOG DEVICES

Low Noise, Precision CMOS Amplifier

AD8655/AD8656

FEATURES

Low noise: 2.7 nV/√Hz @ f = 10 kHz
Low offset voltage: 250 μV max over V_{CM}
Offset voltage drift: 0.4 μV/°C typ and 2.3 μV/°C max
Bandwidth: 28 MHz
Rail-to-rail input/output
Unity gain stable
2.7 V to 5.5 V operation
−40°C to +125°C operation

APPLICATIONS

ADC and DAC buffers
Audio
Industrial controls
Precision filters
Digital scales
Strain gauges
PLL filters

PIN CONFIGURATIONS

Figure 1. AD8655
8-Lead MSOP (RM-8)
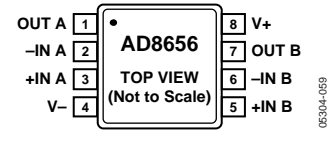
Figure 2. AD8656
8-Lead MSOP (RM-8)
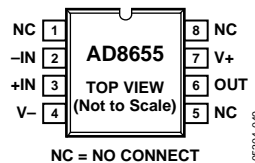
Figure 3. AD8655
8-Lead SOIC (R-8)

Figure 4. AD8656
8-Lead SOIC (R-8)

GENERAL DESCRIPTION

The AD8655/AD8656 are the industry's lowest noise, precision CMOS amplifiers. They leverage the Analog Devices DigiTrim® technology to achieve high dc accuracy.

The AD8655/AD8656 provide low noise (2.7 nV/√Hz @ 10 kHz), low THD + N (0.0007%), and high precision performance (250 μV max over V_{CM}) to low voltage applications. The ability to swing rail-to-rail at the input and output enables designers to buffer analog-to-digital converters (ADCs) and other wide dynamic range devices in single-supply systems.
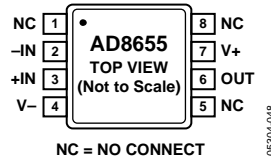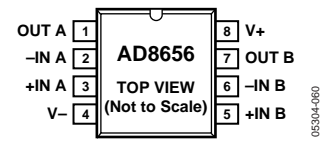
The high precision performance of the AD8655/AD8656 improves the resolution and dynamic range in low voltage applications. Audio applications, such as microphone pre-amps and audio mixing consoles, benefit from the low noise, low distortion, and high output current capability of the AD8655/ AD8656 to reduce system level noise performance and maintain audio fidelity. The high precision and rail-to-rail input and output of the AD8655/AD8656 benefit data acquisition, process controls, and PLL filter applications.

The AD8655/AD8656 are fully specified over the −40°C to +125°C temperature range. The AD8655/AD8656 are available in Pb-free, 8-lead MSOP and SOIC packages.

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REVISION HISTORY

SPECIFICATIONS

V_S = 5.0 V, V_{CM} = V_S/2, T_A = 25°C, unless otherwise specified.

Table 1.

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
INPUT CHARACTERISTICS						
Offset Voltage	V_{OS}	V_{CM} = 0 V to 5 V		50	250	µV
		−40°C ≤ T_A ≤ +125°C			550	µV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$	−40°C ≤ T_A ≤ +125°C		0.4	2.3	µV/°C
Input Bias Current	I_B			1	10	pA
		−40°C ≤ T_A ≤ +125°C			500	pA
Input Offset Current	I_{OS}				10	pA
		−40°C ≤ T_A ≤ +125°C			500	pA
Input Voltage Range			0		5	V
Common-Mode Rejection Ratio	CMRR	V_{CM} = 0 V to 5 V	85	100		dB
Large Signal Voltage Gain	A_{VO}	V_O = 0.2 V to 4.8 V, R_L = 10 kΩ, V_{CM} = 0 V	100	110		dB
		−40°C ≤ T_A ≤ +125°C	95			dB
OUTPUT CHARACTERISTICS						
Output Voltage High	V_{OH}	I_L = 1 mA; −40°C ≤ T_A ≤ +125°C	4.97	4.991		V
Output Voltage Low	V_{OL}	I_L = 1 mA; −40°C ≤ T_A ≤ +125°C		8	30	mV
Output Current	I_{OUT}	V_{OUT} = ±0.5 V		±220		mA
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	V_S = 2.7 V to 5.0 V	88	105		dB
Supply Current/Amplifier	I_{SY}	V_O = 0 V		3.7	4.5	mA
		−40°C ≤ T_A ≤ +125°C			5.3	mA
INPUT CAPACITANCE	C_{IN}					
Differential				9.3		pF
Common-Mode				16.7		pF
NOISE PERFORMANCE						
Input Voltage Noise Density	e_n	f = 1 kHz		4		nV/√Hz
		f = 10 kHz		2.7		nV/√Hz
Total Harmonic Distortion + Noise	THD + N	G = 1, R_L = 1 kΩ, f = 1 kHz, V_{IN} = 2 V p-p		0.0007		%
FREQUENCY RESPONSE						
Gain Bandwidth Product	GBP			28		MHz
Slew Rate	SR	R_L = 10 kΩ		11		V/µs
Settling Time	ts	To 0.1%, V_{IN} = 0 V to 2 V step, G = +1		370		ns
Phase Margin		C_L = 0 pF		69		degrees

$V_S = 2.7$ V, $V_{CM} = V_S/2$, $T_A = 25°C$, unless otherwise specified.

Table 2.

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
INPUT CHARACTERISTICS						
Offset Voltage	V_{OS}	V_{CM} = 0 V to 2.7 V		44	250	μV
		−40°C ≤ T_A ≤ +125°C			550	μV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$	−40°C ≤ T_A ≤ +125°C		0.4	2.0	μV/°C
Input Bias Current	I_B			1	10	pA
		−40°C ≤ T_A ≤ +125°C			500	pA
Input Offset Current	I_{OS}				10	pA
		−40°C ≤ T_A ≤ +125°C			500	pA
Input Voltage Range			0		2.7	V
Common-Mode Rejection Ratio	CMRR	V_{CM} = 0 V to 2.7 V	80	98		dB
Large Signal Voltage Gain	A_{VO}	V_O = 0.2 V to 2.5 V, R_L = 10 kΩ, V_{CM} = 0 V	98			dB
		−40°C ≤ T_A ≤ +125°C	90			dB
OUTPUT CHARACTERISTICS						
Output Voltage High	V_{OH}	I_L = 1 mA; −40°C ≤ T_A ≤ +125°C	2.67	2.688		V
Output Voltage Low	V_{OL}	I_L = 1 mA; −40°C ≤ T_A ≤ +125°C		10	30	mV
Output Current	I_{OUT}	V_{OUT} = ±0.5 V		±75		mA
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	V_S = 2.7 V to 5.0 V	88	105		dB
Supply Current/Amplifier	I_{SY}	V_O = 0 V		3.7	4.5	mA
		−40°C ≤ T_A ≤ +125°C			5.3	mA
INPUT CAPACITANCE	C_{IN}					
Differential				9.3		pF
Common-Mode				16.7		pF
NOISE PERFORMANCE						
Input Voltage Noise Density	e_n	f = 1 kHz		4.0		nV/√Hz
		f = 10 kHz		2.7		nV/√Hz
Total Harmonic Distortion + Noise	THD + N	G = 1, R_L = 1kΩ, f = 1 kHz, V_{IN} = 2 V p-p		0.0007		%
FREQUENCY RESPONSE						
Gain Bandwidth Product	GBP			27		MHz
Slew Rate	SR	R_L = 10 kΩ		8.5		V/μs
Settling Time	ts	To 0.1%, V_{IN} = 0 to 1 V step, G = +1		370		ns
Phase Margin		C_L = 0 pF		54		degrees

ABSOLUTE MAXIMUM RATINGS

Table 3.

Parameter	Rating
Supply Voltage	6 V
Input Voltage	VSS − 0.3 V to VDD + 0.3 V
Differential Input Voltage	±6 V
Output Short-Circuit Duration to GND	Indefinite
Electrostatic Discharge (HBM)	3.0 kV
Storage Temperature Range R, RM Packages	−65°C to +150°C
Junction Temperature Range R, RM Packages	−65°C to +150°C
Lead Temperature (Soldering, 10 sec)	260°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 4.

Package Type	θ_{JA}[1]	θ_{JC}	Unit
8-Lead MSOP (RM)	210	45	°C/W
8-Lead SOIC (R)	158	43	°C/W

[1]θ_{JA} is specified for worst-case conditions; that is, θ_{JA} is specified for a device soldered in the circuit board for surface-mount packages.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

WARNING!

ESD SENSITIVE DEVICE

TYPICAL PERFORMANCE CHARACTERISTICS
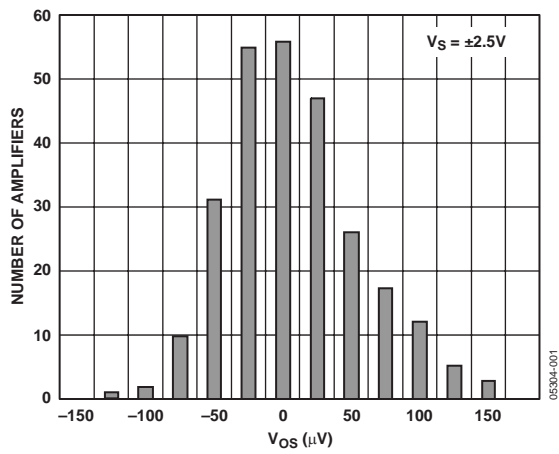
Figure 5. Input Offset Voltage Distribution

Figure 6. Input Offset Voltage vs. Temperature

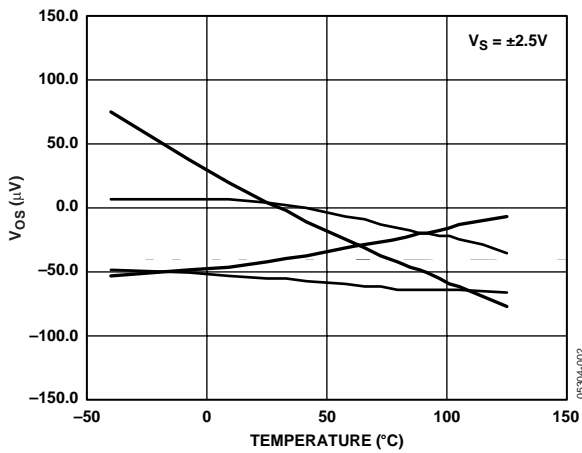Figure 7. |TCV$_{OS}$| Distribution

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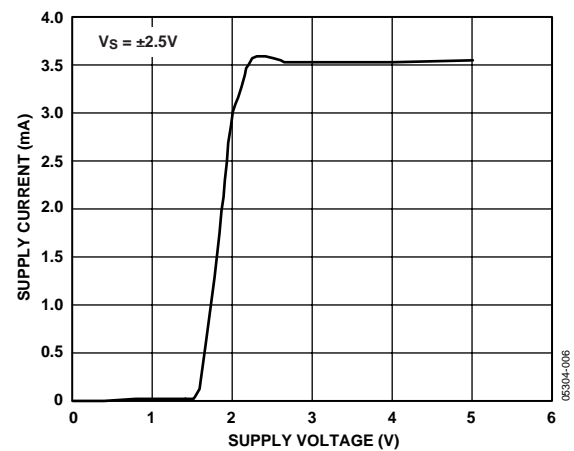

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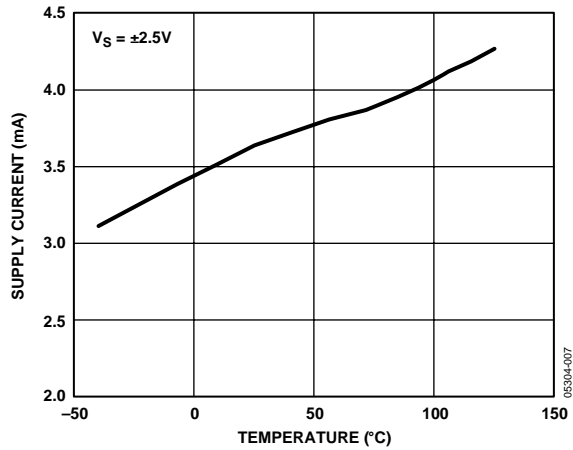
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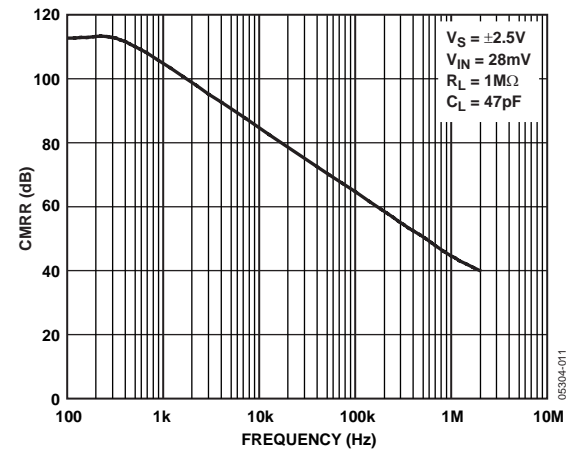
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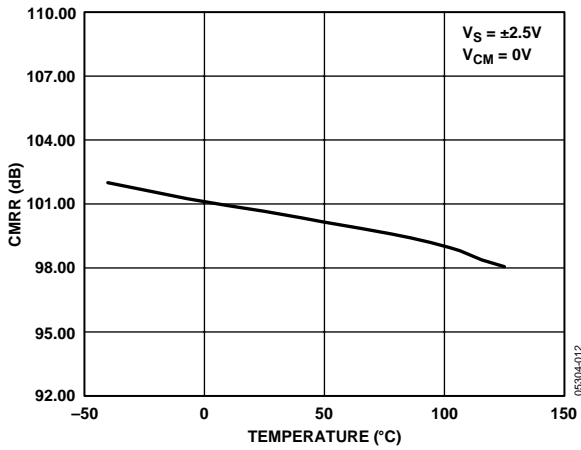
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Figure 19. Large Signal PSSR vs. Temperature

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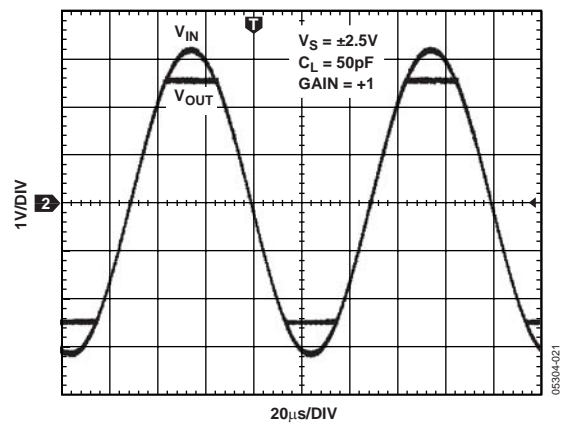
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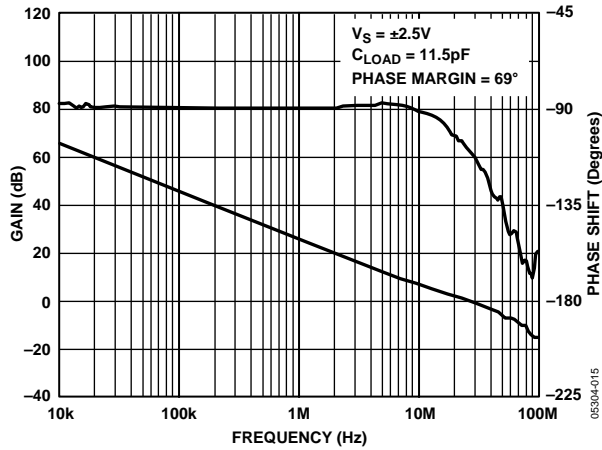
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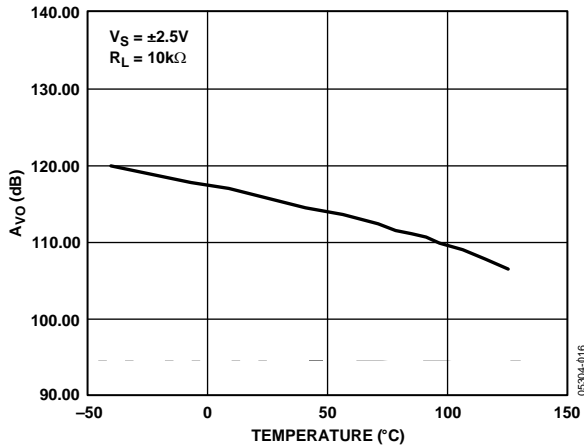

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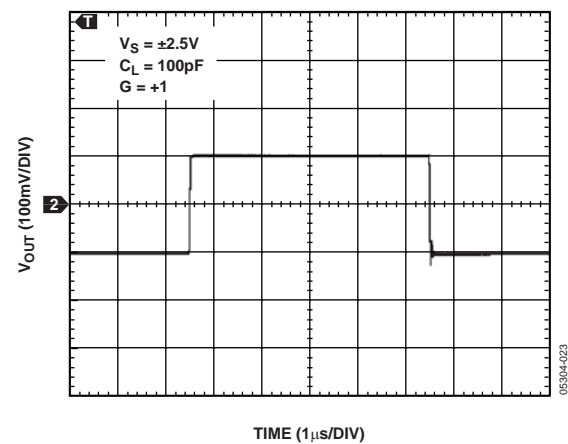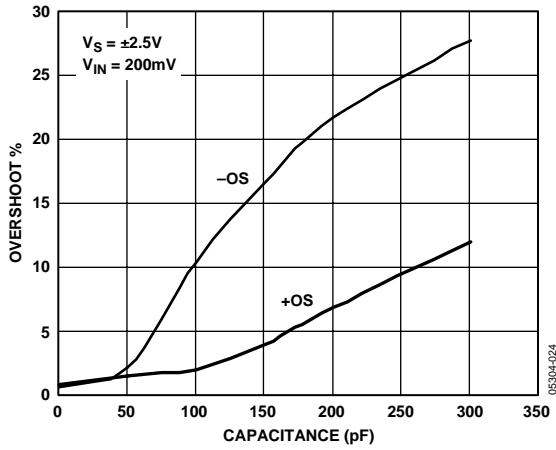
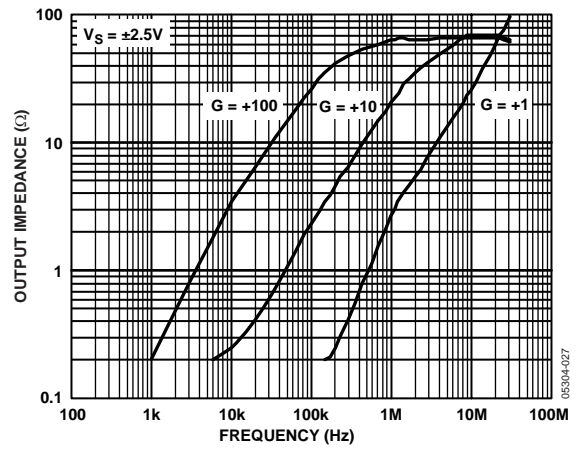Figure 29. Small Signal Overshoot vs. Load Capacitance

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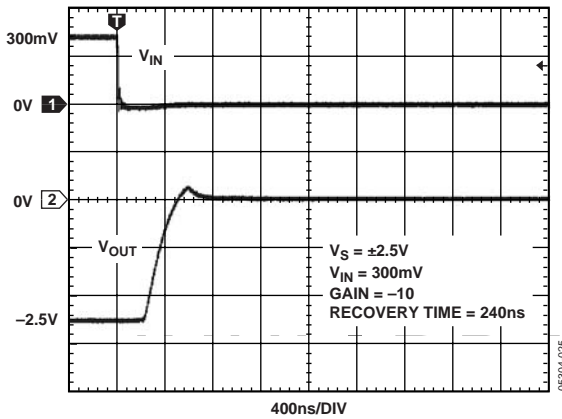
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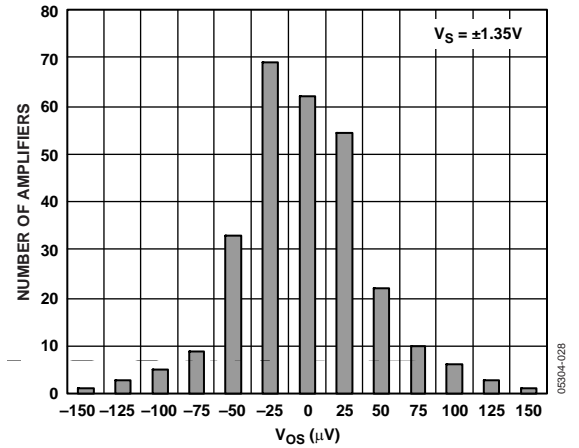
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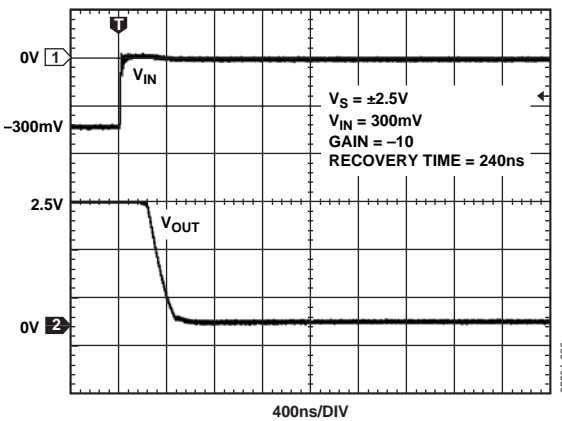
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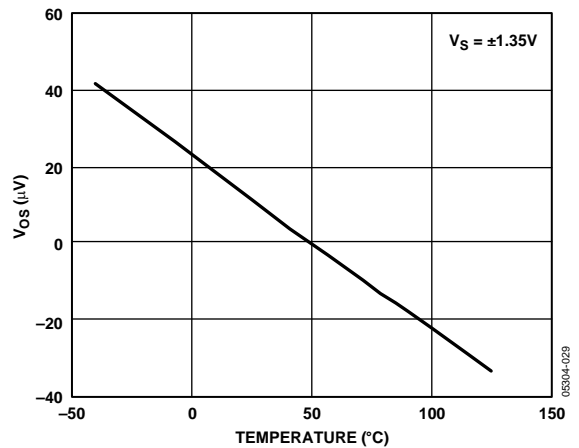
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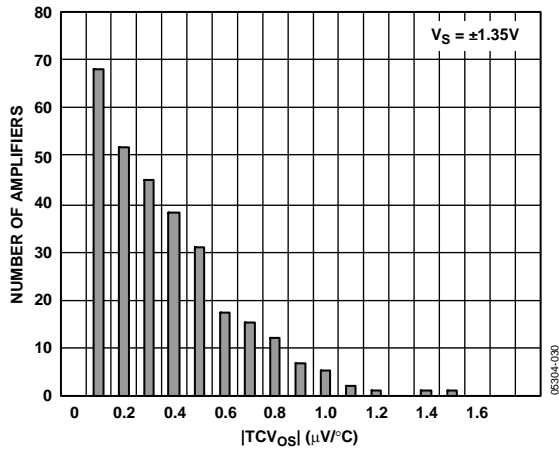
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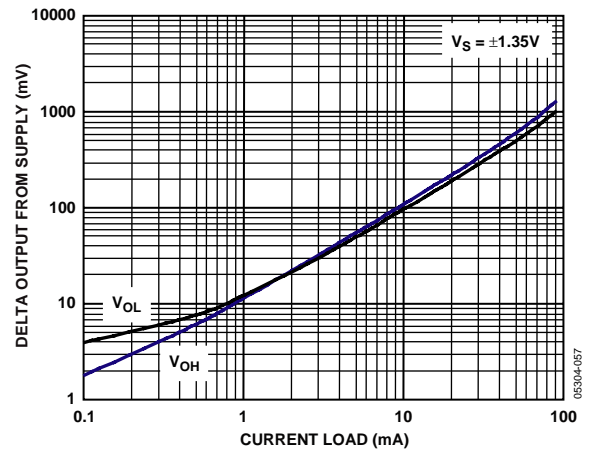
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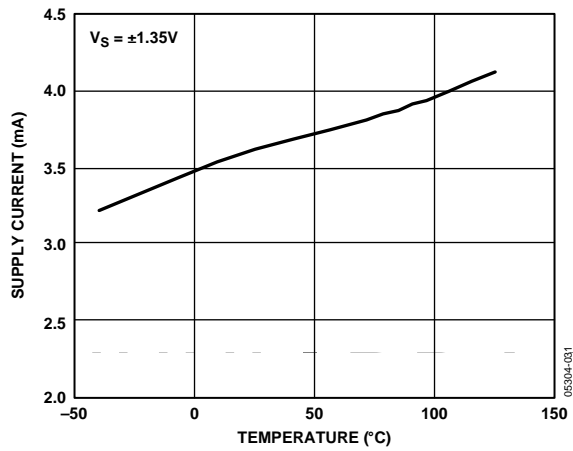
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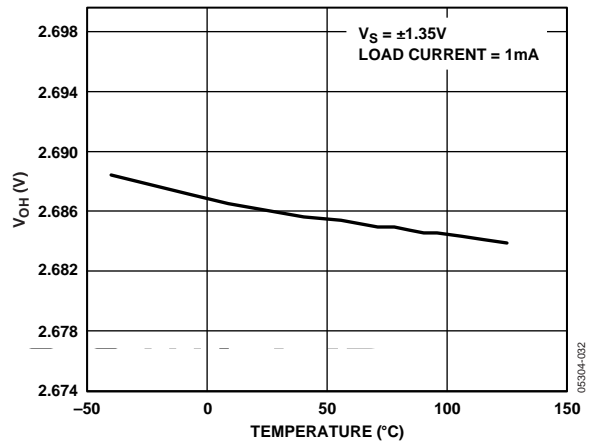
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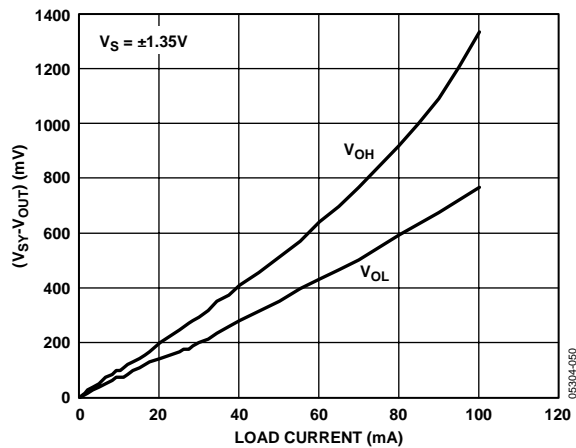
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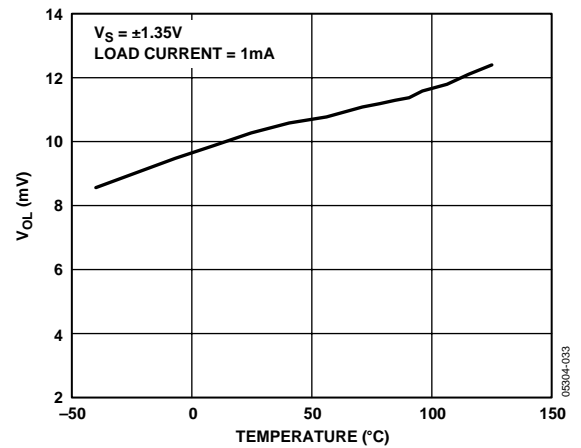
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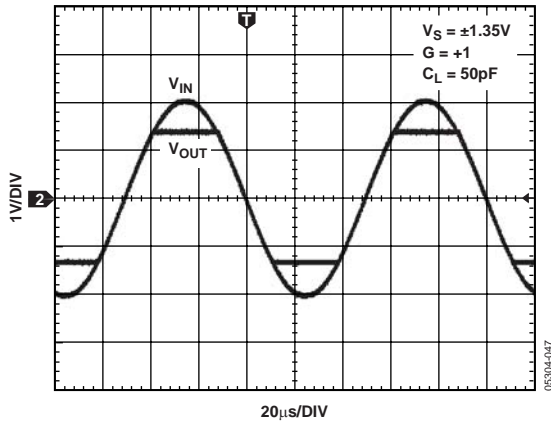
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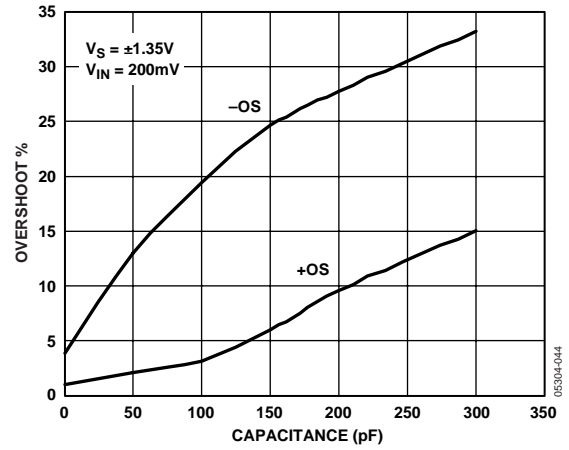
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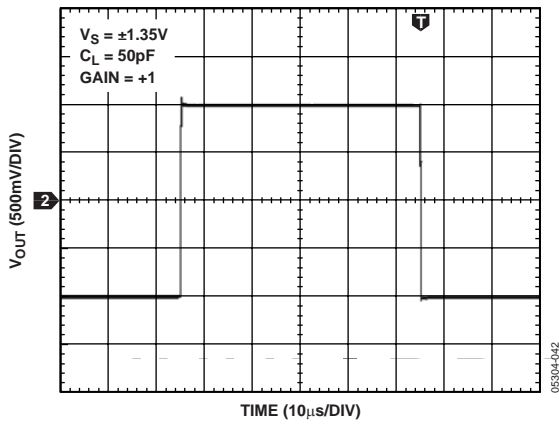
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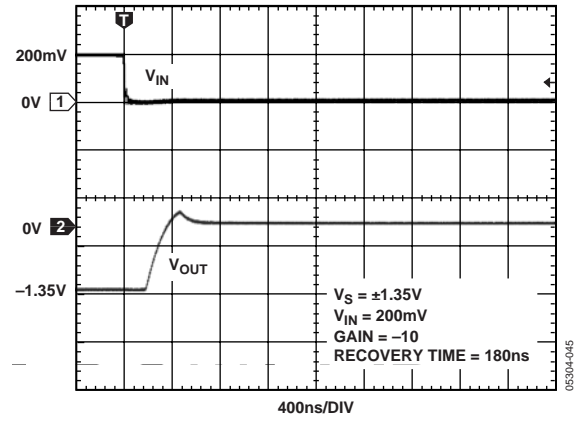
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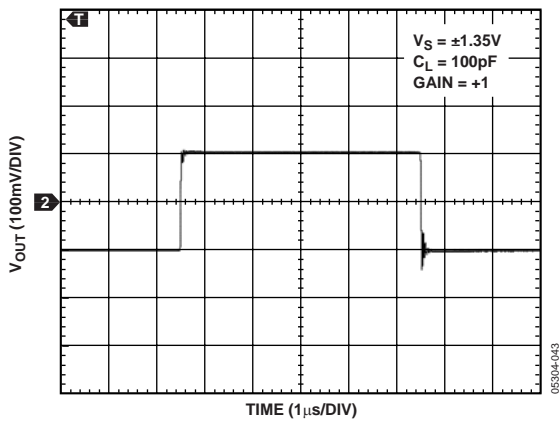
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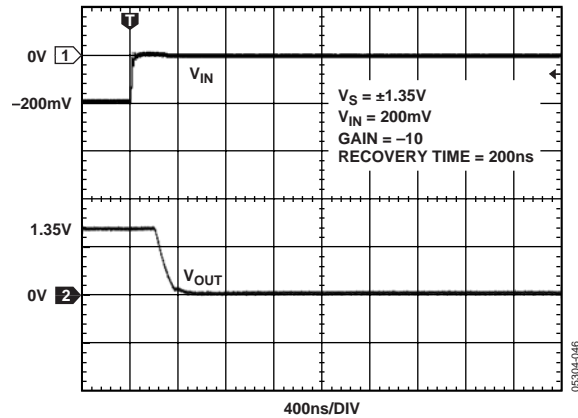
Figure 46. Positive Overload Recovery Time
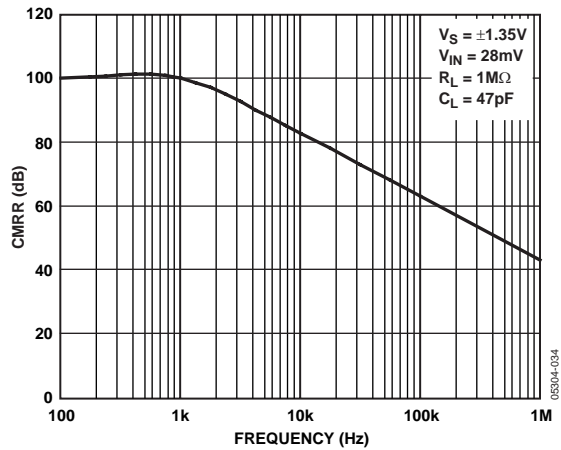
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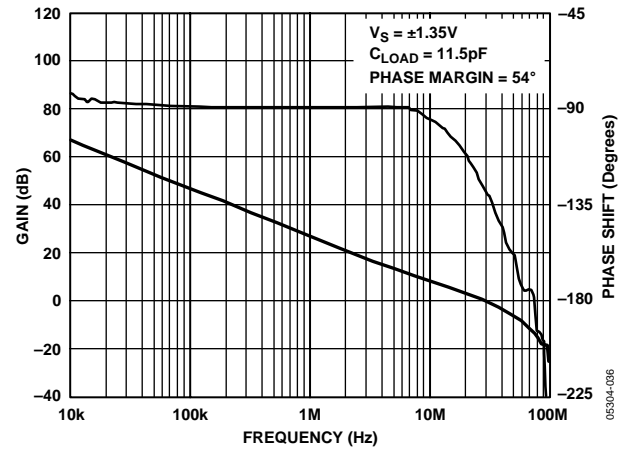
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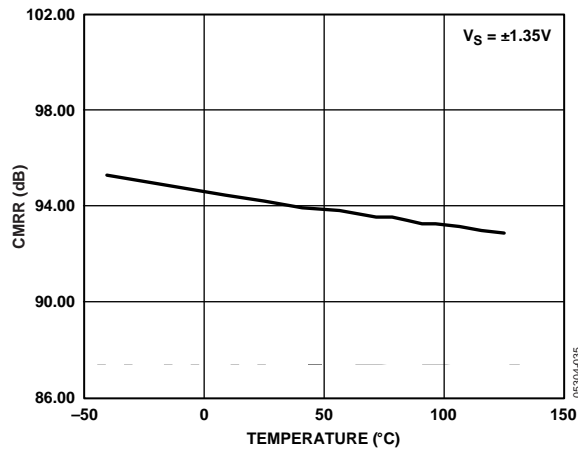
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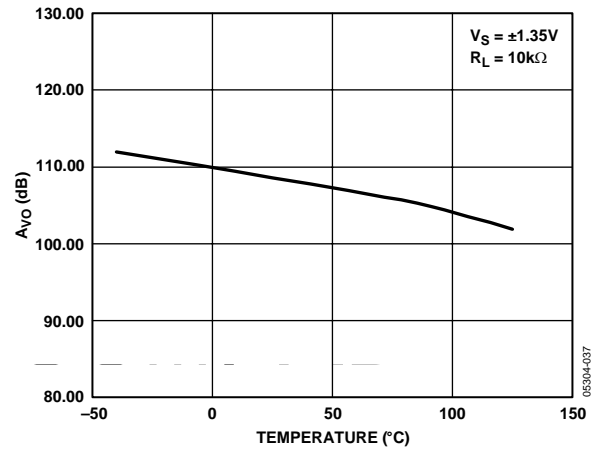
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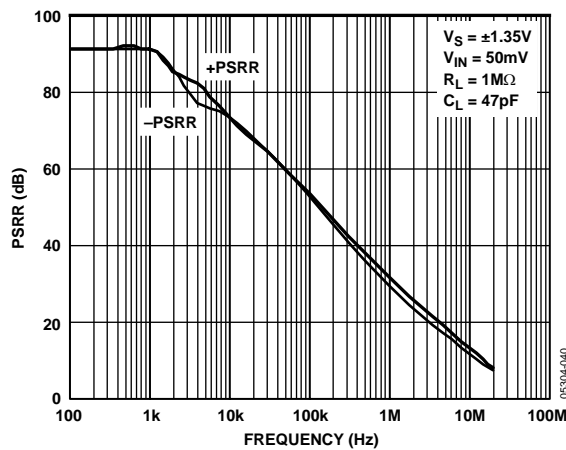
Figure 49. Small Signal PSSR vs. Frequency
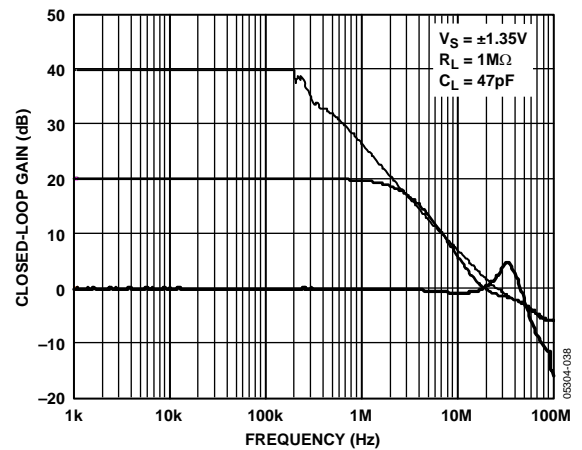
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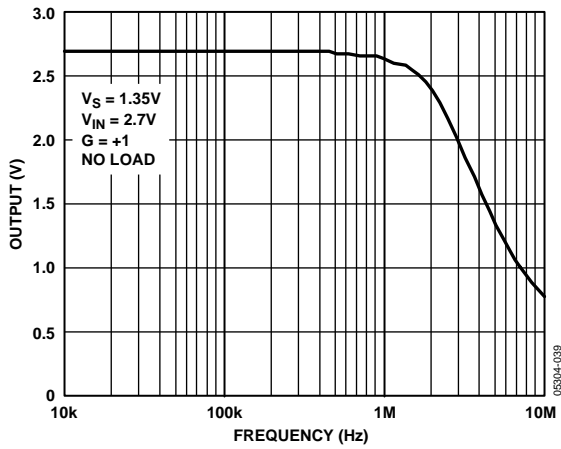
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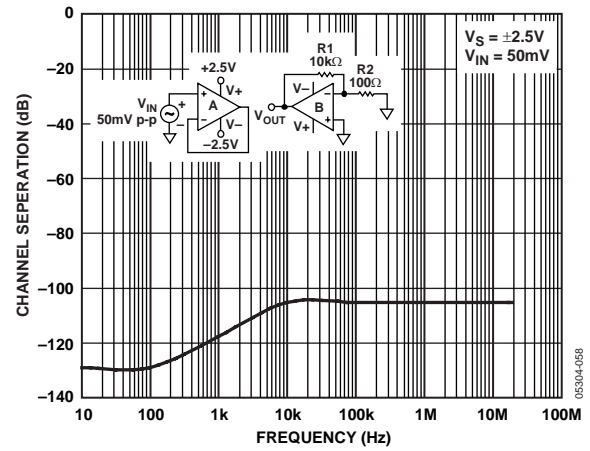
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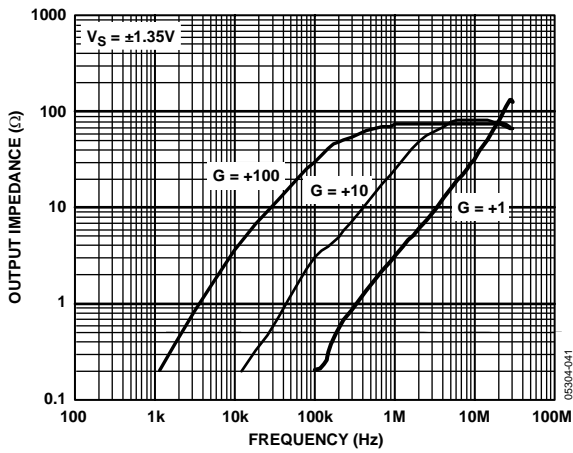
Figure 54. Output Impedance vs. Frequency

THEORY OF OPERATION

The AD8655/AD8656 amplifiers are voltage feedback, rail-to-rail input and output precision CMOS amplifiers, which operate from 2.7 V to 5.0 V of power supply voltage. These amplifiers use the Analog Devices DigiTrim technology to achieve a higher degree of precision than is available from most CMOS amplifiers. DigiTrim technology, used in a number of ADI amplifiers, is a method of trimming the offset voltage of the amplifier after it is packaged. The advantage of post-package trimming is that it corrects any offset voltages caused by the mechanical stresses of assembly.

The AD8655/AD8656 are available in standard op amp pinouts, making DigiTrim completely transparent to the user. The input stage of the amplifiers is a true rail-to-rail architecture, allowing the input common-mode voltage range of the amplifiers to extend to both positive and negative supply rails. The open-loop gain of the AD8655/AD8656 with a load of 10 kΩ is typically 110 dB.

The AD8655/AD8656 can be used in any precision op amp application. The amplifier does not exhibit phase reversal for common-mode voltages within the power supply. The AD8655/AD8656 are great choices for high resolution data acquisition systems with voltage noise of 2.7 nV/√Hz and THD + Noise of −103 dB for a 2 V p-p signal at 10 kHz. Their low noise, sub-pA input bias current, precision offset, and high speed make them superb preamps for fast filter applications. The speed and output drive capability of the AD8655/AD8656 also make them useful in video applications.

APPLICATIONS

INPUT OVERVOLTAGE PROTECTION

The internal protective circuitry of the AD8655/AD8656 allows voltages exceeding the supply to be applied at the input. It is recommended, however, not to apply voltages that exceed the supplies by more than 0.3 V at either input of the amplifier. If a higher input voltage is applied, series resistors should be used to limit the current flowing into the inputs. The input current should be limited to less than 5 mA.

The extremely low input bias current allows the use of larger resistors, which allows the user to apply higher voltages at the inputs. The use of these resistors adds thermal noise, which contributes to the overall output voltage noise of the amplifier. For example, a 10 kΩ resistor has less than 12.6 nV/√Hz of thermal noise and less than 10 nV of error voltage at room temperature.

INPUT CAPACITANCE

Along with bypassing and ground, high speed amplifiers can be sensitive to parasitic capacitance between the inputs and ground. For circuits with resistive feedback network, the total capacitance, whether it is the source capacitance, stray capacitance on the input pin, or the input capacitance of the amplifier, causes a breakpoint in the noise gain of the circuit. As a result, a capacitor must be added in parallel with the gain resistor to obtain stability. The noise gain is a function of frequency and peaks at the higher frequencies, assuming the feedback capacitor is selected to make the second-order system critically damped. A few picofarads of capacitance at the input reduce the input impedance at high frequencies, which increases the amplifier's gain, causing peaking in the frequency response or oscillations. With the AD8655/AD8656, additional input damping is required for stability with capacitive loads greater than 200 pF with direct input to output feedback. See the Driving Capacitive Loads section.

DRIVING CAPACITIVE LOADS

Although the AD8655/AD8656 can drive capacitive loads up to 500 pF without oscillating, a large amount of ringing is present when operating the part with input frequencies above 100 kHz. This is especially true when the amplifiers are configured in positive unity gain (worst case). When such large capacitive loads are required, the use of external compensation is highly recommended. This reduces the overshoot and minimizes ringing, which, in turn, improves the stability of the AD8655/AD8656 when driving large capacitive loads.

One simple technique for compensation is a snubber that consists of a simple RC network. With this circuit in place, output swing is maintained, and the amplifier is stable at all gains. Figure 57 shows the implementation of a snubber, which reduces overshoot by more than 30% and eliminates ringing. Using a snubber does not recover the loss of bandwidth incurred from a heavy capacitive load.
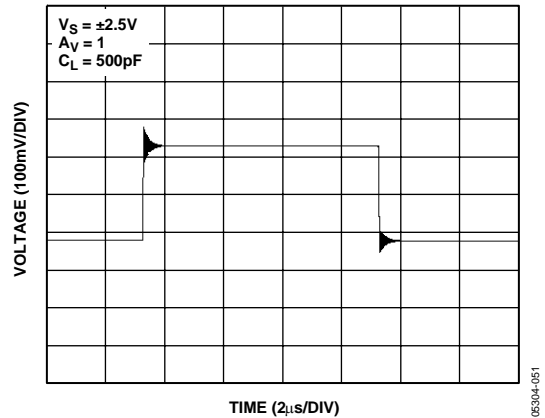
Figure 56. Driving Heavy Capacitive Loads Without Compensation
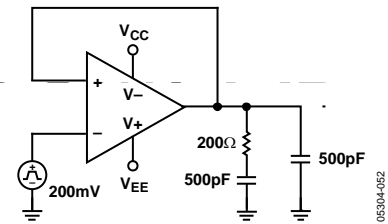
Figure 57. Snubber Network
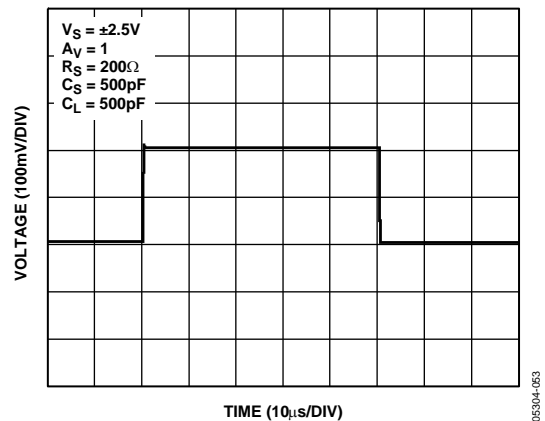
Figure 58. Driving Heavy Capacitive Loads Using a Snubber Network

THD Readings vs. Common-Mode Voltage

Total harmonic distortion of the AD8655/AD8656 is well below 0.0007% with a load of 1 kΩ. This distortion is a function of the circuit configuration, the voltage applied, and the layout, in addition to other factors.

Figure 59. THD + N Test Circuit

Figure 60. THD + Noise vs. Frequency

LAYOUT, GROUNDING, AND BYPASSING CONSIDERATIONS

POWER SUPPLY BYPASSING

Power supply pins can act as inputs for noise, so care must be taken to apply a noise-free, stable dc voltage. The purpose of bypass capacitors is to create low impedances from the supply to ground at all frequencies, thereby shunting or filtering most of the noise. Bypassing schemes are designed to minimize the supply impedance at all frequencies with a parallel combination of capacitors with values of 0.1 μF and 4.7 μF. Chip capacitors of 0.1 μF (X7R or NPO) are critical and should be as close as possible to the amplifier package. The 4.7 μF tantalum capacitor is less critical for high frequency bypassing, and, in most cases, only one is needed per board at the supply inputs.
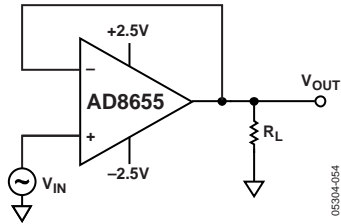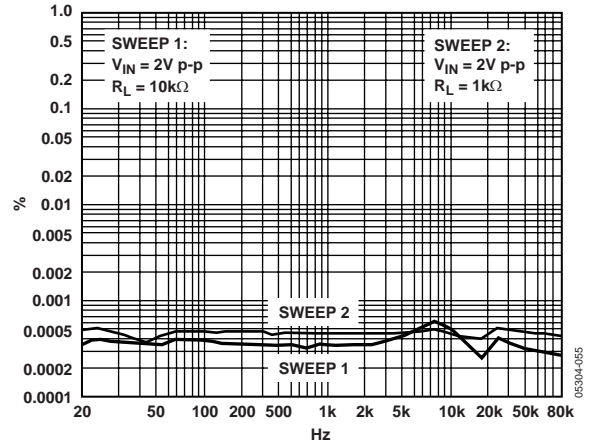
GROUNDING

A ground plane layer is important for densely packed PC boards to minimize parasitic inductances. This minimizes voltage drops with changes in current. However, an under-standing of where the current flows in a circuit is critical to implementing effective high speed circuit design. The length of the current path is directly proportional to the magnitude of parasitic inductances, and, therefore, the high frequency impedance of the path. Large changes in currents in an inductive ground return create unwanted voltage noise.

The length of the high frequency bypass capacitor leads is critical, and, therefore, surface-mount capacitors are recom-mended. A parasitic inductance in the bypass ground trace works against the low impedance created by the bypass capacitor. Because load currents flow from the supplies, the ground for the load impedance should be at the same physical location as the bypass capacitor grounds. For larger value capacitors intended to be effective at lower frequencies, the current return path distance is less critical.

LEAKAGE CURRENTS

Poor PC board layout, contaminants, and the board insulator material can create leakage currents that are much larger than the input bias current of the AD8655/AD8656. Any voltage differential between the inputs and nearby traces creates leakage currents through the PC board insulator, for example, 1 V/100 GΩ = 10 pA. Similarly, any contaminants on the board can create significant leakage (skin oils are a common problem).

To significantly reduce leakage, put a guard ring (shield) around the inputs and input leads that are driven to the same voltage potential as the inputs. This ensures there is no voltage potential between the inputs and the surrounding area to create any leakage currents. To be effective, the guard ring must be driven by a relatively low impedance source and should completely surround the input leads on all sides, above and below, by using a multilayer board.

The charge absorption of the insulator material itself can also cause leakage currents. Minimizing the amount of material between the input leads and the guard ring helps to reduce the absorption. Also, using low absorption materials, such as Teflon® or ceramic, may be necessary in some instances.

OUTLINE DIMENSIONS
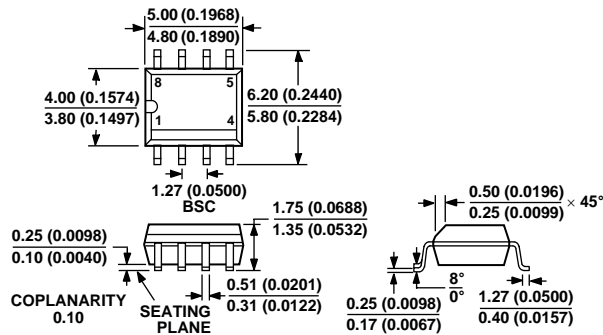
COMPLIANT TO JEDEC STANDARDS MS-012-AA

CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS
(IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR
REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN

Figure 61. 8-Lead Standard Small Outline Package [SOIC_N]
Narrow Body (R-8)
Dimensions shown in millimeters and (inches)
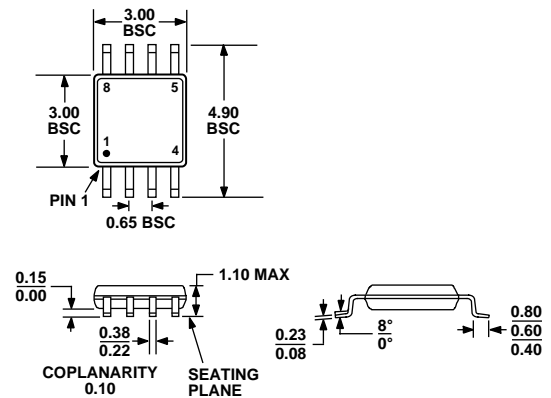
COMPLIANT TO JEDEC STANDARDS MO-187-AA

Figure 62. 8-Lead Mini Small Outline Package [MSOP]
(RM-8)
Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option	Branding
AD8655ARZ[1]	−40°C to +125°C	8-Lead SOIC_N	R-8	
AD8655ARZ-REEL[1]	−40°C to +125°C	8-Lead SOIC_N	R-8	
AD8655ARZ-REEL7[1]	−40°C to +125°C	8-Lead SOIC_N	R-8	
AD8655ARMZ-REEL[1]	−40°C to +125°C	8-Lead MSOP	RM-8	A0D
AD8655ARMZ-R2[1]	−40°C to +125°C	8-Lead MSOP	RM-8	A0D
AD8656ARZ[1]	−40°C to +125°C	8-Lead SOIC_N	R-8	
AD8656ARZ-REEL[1]	−40°C to +125°C	8-Lead SOIC_N	R-8	
AD8656ARZ-REEL7[1]	−40°C to +125°C	8-Lead SOIC_N	R-8	
AD8656ARMZ-REEL[1]	−40°C to +125°C	8-Lead MSOP	RM-8	A0S
AD8656ARMZ-R2[1]	−40°C to +125°C	8-Lead MSOP	RM-8	A0S

[1] Z = Pb-free part.

NOTES

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